

**Notice of References Cited**

Application/Control No.

10/007,572

Applicant(s)/Patent Under Reexam

Lee et al.

Examiner

Cam Nguyen

Art Unit

1754

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	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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**NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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